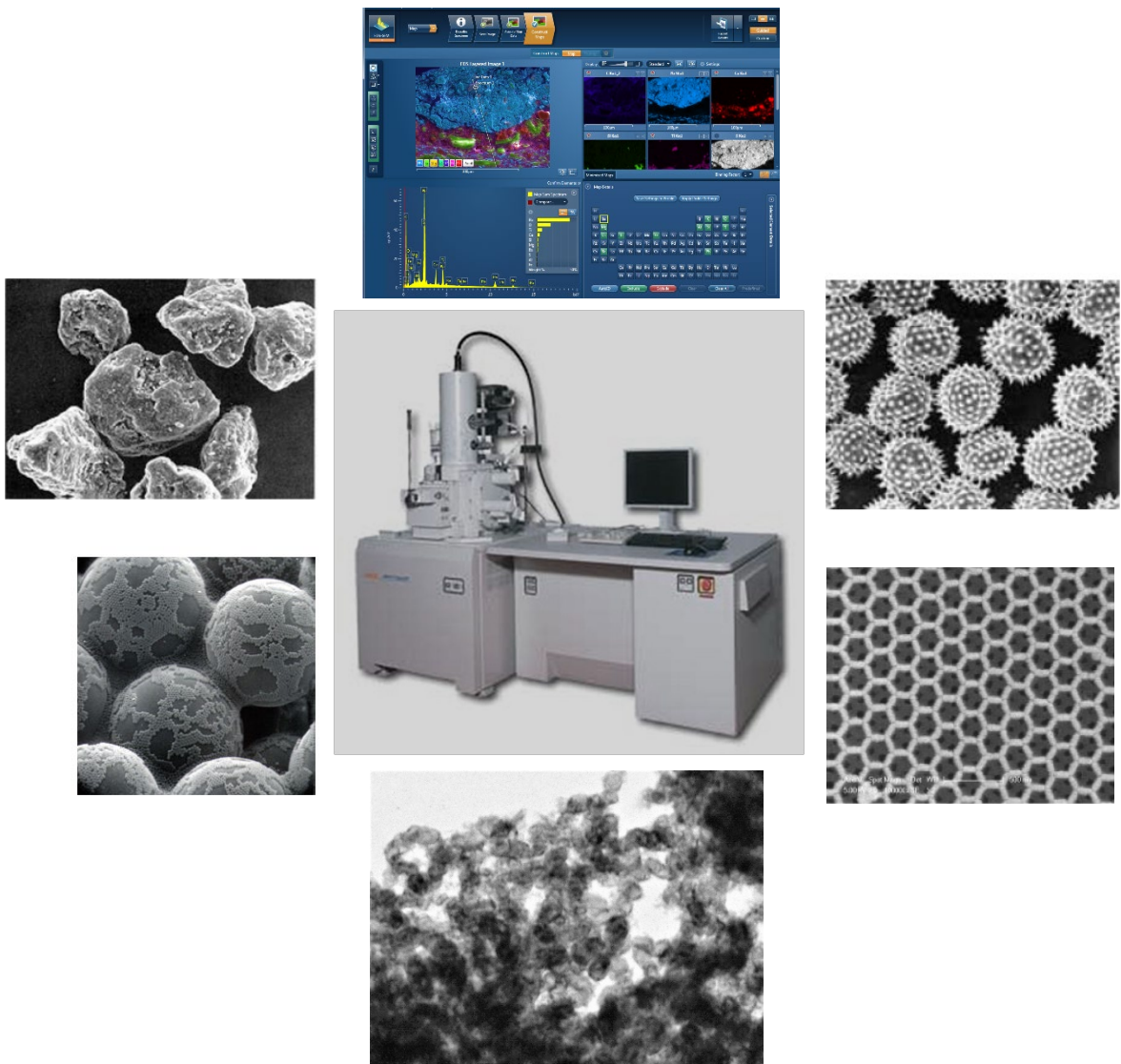


## Field Emission Scanning Electron Microscope (FE-SEM)



The thermal FE-SEM successfully combines ultrahigh resolution imaging with optimized analytical functionality. It is equipped with low-angle backscattered electron detector (BSE), LN2 Free EDS detector and scanning transmission electron detector (STEM).

### Features

- Ultrahigh resolution comparable to the cold cathode FE-SEM. SEI resolution of 1.5 nm (1kV) in GB mode and 1.0 nm (15 kV)
- Magnification of 25 to 1,000,000x
- Accelerating voltage of 0.1 to 30 kV
- Aperture angle control lens automatically optimizes the spot size at both high and low currents for both analysis and imaging.
- Built-in r-filter enabling user selectable mixture of secondary electron and backscattered electron images.
- Gentle Beam mode for top-surface imaging, reduced beam damage and charge suppression. Beam current of 1 pA to 200 nA at 15 kV.

**Brand – JEOL; Model – JSM-7600F**

For enquiries, please contact the staff in-charge: Ms Maria Chong

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